

# HN1B04FU

### Audio Frequency General Purpose Amplifier Applications

Unit: mm

Q1:High voltage and high current

- $: V_{CEO} = 50V, I_C = 150mA (max)$
- High  $h_{FE}$ :  $h_{FE} = 120 \sim 400$
- Excellent hFE linearity

 $h_{\rm FE}$  (IC = 0.1mA) / hFE (IC = 2mA) = 0.95 (typ.)

#### Q2:

- High voltage and high current
  - $: V_{CEO} = -50V, I_{C} = -150mA (max)$

Q1 Absolute Maximum Ratings (Ta = 25°C)

- High hFE:  $hFE = 120 \sim 400$
- Excellent hFE linearity

:  $h_{FE}$  (IC = -0.1mA) /  $h_{FE}$  (IC = -2mA) = 0.95 (typ.)





#### Marking





J1B02

**Equivalent Circuit (Top View)** 

#### Q2 Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector-base voltage	V <sub>CBO</sub>	-50	V
Collector-emitter voltage	V <sub>CEO</sub>	-50	V
Emitter-base voltage	V <sub>EBO</sub>	-5	V
Collector current	Ι <sub>C</sub>	-150	mA
Base current	Ι <sub>Β</sub>	-30	mA



## Q1,Q2 Common Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit
Collector power dissipation	P <sub>C</sub> *	200	mW
Junction temperature	Tj	125	°C
Storage temperature range	T <sub>stg</sub>	-55~125	°C

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the TY Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

\* Total rating

#### Q1 Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	—	$V_{CB} = 60V, I_E = 0$		_	0.1	μA
Emitter cut-off current	I <sub>EBO</sub>	_	V <sub>EB</sub> = 5V, I <sub>C</sub> = 0			0.1	μA
DC current gain	h <sub>FE (Note)</sub>	—	V <sub>CE</sub> = 6V, I <sub>C</sub> = 2mA	120		400	
Collector-emitter saturation voltage	V <sub>CE (sat)</sub>	_	I <sub>C</sub> = 100mA, I <sub>B</sub> = 10mA	_	0.1	0.25	V
Transition frequency	f <sub>T</sub>	-	V <sub>CE</sub> = 10V, I <sub>C</sub> = 1mA	_	150	-	MHz
Collector output capacitance	C <sub>ob</sub>	_	$V_{CB}$ = 10V, I <sub>E</sub> = 0, f = 1MHz	_	2		pF

#### Q2 Electrical Characteristics (Ta = 25°C)

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Collector cut-off current	I <sub>CBO</sub>	_	$V_{CB} = -50V, I_E = 0$	_	_	-0.1	μA
Emitter cut-off current	I <sub>EBO</sub>	_	$V_{EB} = -5V, I_{C} = 0$	—		-0.1	μA
DC current gain	h <sub>FE (Note)</sub>	—	$V_{CE} = -6V, I_C = -2mA$	120		400	
Collector-emitter saturation voltage	V <sub>CE (sat)</sub>	_	I <sub>C</sub> = -100mA, I <sub>B</sub> = -10mA	_	-0.1	-0.3	V
Transition frequency	f <sub>T</sub>	_	V <sub>CE</sub> = -10V, I <sub>C</sub> = -1mA	—	120		MHz
Collector output capacitance	C <sub>ob</sub>	_	$V_{CB} = -10V$ , $I_E = 0$ , f = 1MHz	_	4		pF

Note: hFE Classification Y (Y): 120~240, GR (G): 200~400

( ) Marking Symbol